

**Search Notes**

Application/Control No.

10/720,354

Examiner

Tran N. Nguyen

Applicant(s)/Patent under  
Reexamination

HAMA ET AL.

Art Unit

2834

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
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